

Application/Control No.	Applicant(s)/Patent under Reexamination	ır	
10/791,825	INOUE, TAKAHIRO	E, TAKAHIRO_	
Examiner	Art Unit		
Long Nauven	2816		

	SEARCHED		
Class	Subclass	Date	Examiner
327	427,429 432–434, 108,	5/4/05	2
	376, 377		1
326	82-84,89	J	1
upolok	asve	12/12/05	2N
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INI	NTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East	5/4/05	W	
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